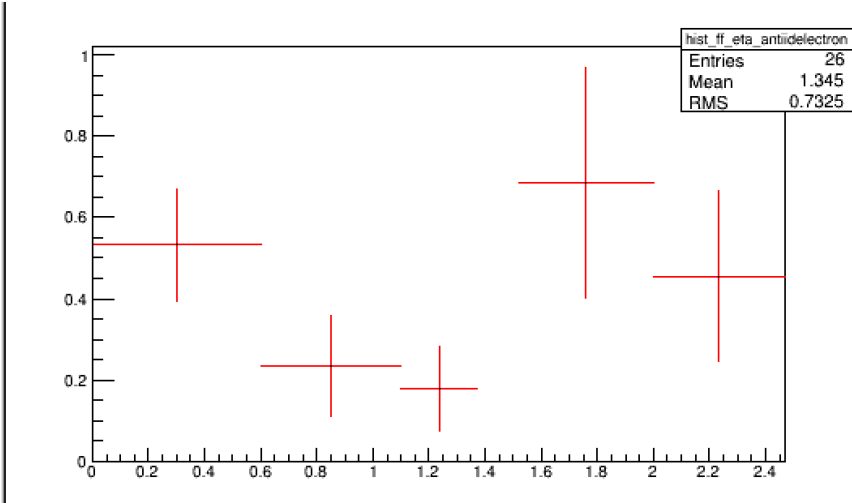
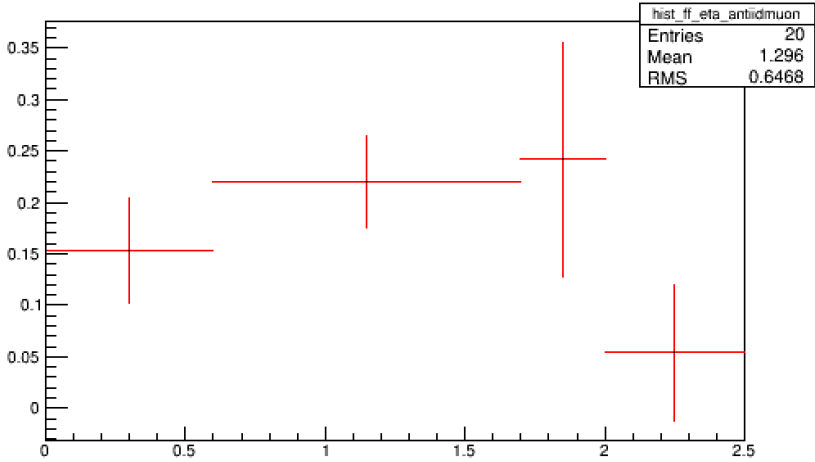


Weekly Report

Fake factor check



Electron



Muon

Matrix Method introduction

- Standard Matrix Method
- Define two efficiencies

- Real lepton $r = \frac{N_{tight}^{real}}{N_{loose}^{real}}$, fake lepton $f = \frac{N_{tight}^{fake}}{N_{loose}^{fake}}$,

- One lepton case

$$N^T = \varepsilon_r N^r + \varepsilon_f N^f$$

$$N^{\bar{T}} = \varepsilon_{\bar{r}} N^r + \varepsilon_{\bar{f}} N^f$$

- Where $r/\equiv 1-r$, $f/\equiv 1-f$
- relate the unknown number of real and fake leptons (N_r , N_f) to observables.

Matrix Method

- Two lepton case

$$\begin{pmatrix} N_{TT} \\ N_{TL'} \\ N_{L'T} \\ N_{L'L'} \end{pmatrix} = \begin{pmatrix} r_1 r_2 & r_1 f_2 & f_1 r_2 & f_1 f_2 \\ r_1(1-r_2) & r_1(1-f_2) & f_1(1-r_2) & f_1(1-f_2) \\ (1-r_1)r_2 & (1-r_1)f_2 & (1-f_1)r_2 & (1-f_1)f_2 \\ (1-r_1)(1-r_2) & (1-r_1)(1-f_2) & (1-f_1)(1-r_2) & (1-f_1)(1-f_2) \end{pmatrix} \begin{pmatrix} N_{RR} \\ N_{RF} \\ N_{FR} \\ N_{FF} \end{pmatrix}$$

- Numbers of different kinds of pairs($N_{TT}, N'_{TL} \dots$) are known
- r, f can be measured in event-enriched regions

Solve the matrix

- Assume efficiency is identical for e from e+e- pair
 - $r_1=r_2, f_1=f_2$

$$\begin{pmatrix} N_{RR} \\ N_{RF} \\ N_{FR} \\ N_{FF} \end{pmatrix} = \frac{1}{(r-f)^2} \begin{pmatrix} (1-f)^2 & (f-1)f & f(f-1) & f^2 \\ (f-1)(1-r) & (1-f)r & f(1-r) & -rf \\ (r-1)(1-f) & (1-r)f & r(1-f) & -rf \\ (1-r)^2 & (r-1)r & r(r-1) & r^2 \end{pmatrix} \begin{pmatrix} N_{TT} \\ N_{TL'} \\ N_{L'T} \\ N_{L'L'} \end{pmatrix}$$

$$\begin{aligned} N_{TT}^{\text{fakes}} = & \alpha[2rf(f-1)(1-r) + f^2(1-r)^2]N_{TT} \\ & + \alpha(1-f)fr^2(N_{TL'} + N_{L'T}) \\ & - \alpha r^2 f^2 N_{L'L'} \end{aligned}$$

- Then number of fakes can be derived
- $N_{TT}^{\text{fakes}} = N^{rf} + N^{fr} + N^{ff}$ at least one fakes in SR.(two Tight)

FakeBkgTool

- Still working on the code
- Now this package has been installed properly out of athena environment.
- Function
 - Provide a standard matrix method and fake factor method implement
 - Input: efficiencies for fake and real leptons
 - Lack of instruction to follow up

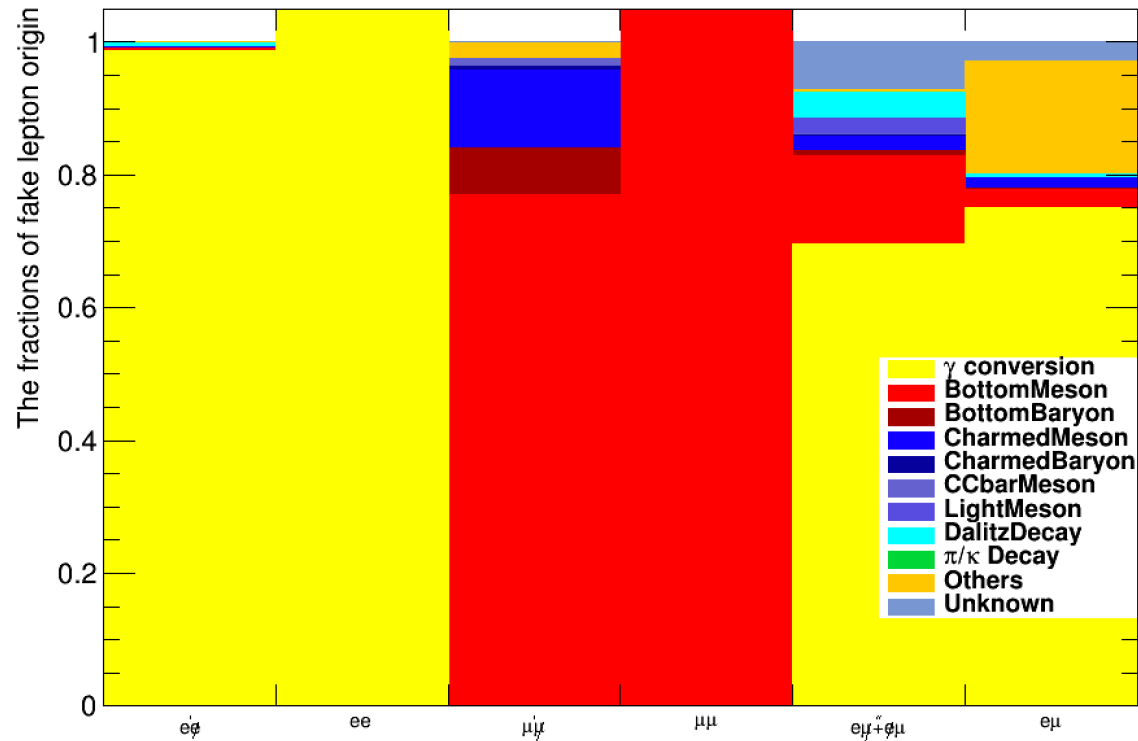
Events critiria

electron			
	Loose	Tight	Anti-Tight
D0sig	5	5	5
Z0sintheta	0.5mm	0.5mm	0.5mm
Electron ID	LooseLH	Tight LH	Fail one of tight requirements
Isolation	FixedCutLoose WP		
Non-prompt rejection	PromptLeptonVeto<-0.7		
Qmis rejection	QMisIDBDT>0.7		

muon			
	Loose	Tight	Anti-tight
D0sig	3	3	3
Z0sintheta	0.5mm	0.5mm	0.5mm
Electron ID	Medium	Tight	Fail one of tight requirements
Isolation	FixedPFlowLoose WP		
Non-prompt rejection	PromptLeptonVeto<-0.5		

Loose = tight +anti-tight

Fake composition



Tight+anti-tight leptons CR

Tight-Tight leptons pre SR

- Most of the fake electrons arise from
- While muon are from HF
- Need to be checked

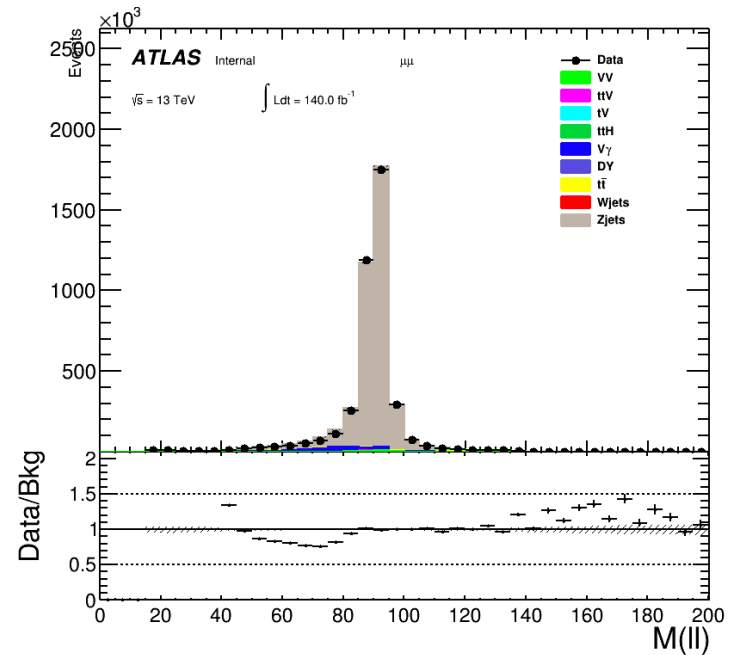
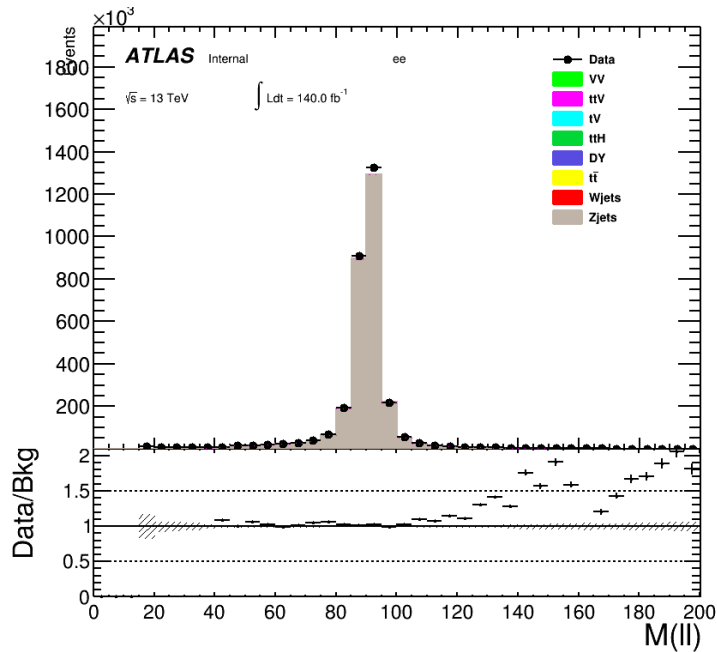
To do list

- In new releases photon conversion using the conversion radius and m_{track_track} can be separated to
 - Material CO
 - Internal CO

Using $m(trk - trk)$ at PV and conv. vertex radius and mass:
External CR ($r > 20\text{mm}$ and $0 < m(trk-trk)_{at PV} < 100\text{MeV}$)
Internal CR (not External and $0 < m(trk-trk)_{at PV} < 100\text{MeV}$)

- Defined CR regions
- efficiencies measurement
- Applied to data

Real lepton efficiency measurement



- To select prue Z->ee/mumu events
- Consider Tag&probe method
 - One Tight lepton(Tag) one go though loose
 - Something overestimated in mumu channel